

size of solid electrolyte elements(110)is in the range of about 1-50nm (electrolyte in the range of 25-75 nm, see column 3, paragraph 0037).

The applicant disagrees above explanation about Figure 3 of Gilton's invention (US.2003/0194865). Below is the paragraph 0037 of Gilton's invention (US.2003/0194865).

"In the illustrated embodiment, the glass electrolyte material 110 comprises a chalcogenide glass with metal ions diffused therein, more preferably silver GeAs, typically of the form Ag/GeAs. The thickness of the Ag/GeAs layer is preferably between 25-75 nm. There is some Ag film 112 remaining over the glass after Ag ions have been driven into the GeAs, whether left over from photodissolution or deposited after forming the electrolyte 110."

The applicant can not see any description in above paragraph about "resistive layer with a plurality of solid electrolyte element" as the explanation of examiner. Applicant requests that examiner review his explanation.

Response to Arguments

Applicant argue, on page 2, paragraph 1, that Gilton fail to discloses a resistive layer with "a plurality of solid electrolyte" embedded therewithin and metal layer there on.

Examiner disagrees, Gilton disclosed a metal film (112) is deposited over a resistive layer (110) formed of electrolyte element, see paragraph 0024.

Applicant has not claimed any special arrangement or types of electrolyte element.

Applicant argues, on page 2, paragraph 2, the memory cell of Gilton includes only pillar. The pillar structure of Gilton is completely different from the cell structure of applicant.

Examiner disagrees. Applicant has not claimed any specific configuration to differentiate the claimed structure from that shown by Gilton.

Applicant has claimed a memory cell structure with a porous dielectric layer having a plurality of pores filled with solid electrolyte material. New claims 35-41 are added to define the applicant's memory cell structure that is different from Gilton's memory structure.

Based on the above reasons, applicant requests the examiner to withdraw the rejection.

Conditional Request for Constructive Assistance

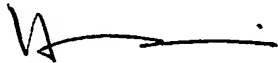
Applicant has amended the specification and claims of this application so that they are proper, and define novel structure which is also unobvious. If, for

any reason this application is not believed to be in full condition for allowance, applicant respectfully request the constructive assistance and suggestions of the Examiner pursuant to M.P.E.P. § 2173.02 and § 707.07(j) in order that the undersigned can place this application in allowable condition as soon as possible and without the need for further proceedings.

Request for telephone or personal interview

In case that the examiner still disagree the applicant amendment, the applicant request a telephone or personal interview to explain in more detail about the invention.


Very respectfully,



Hai Jiang

Certificate of Mailing: I certify that on the date below this document and referenced attachments, if any, will be deposited with the USPS as express mail (Label #: ED 812037163 US) with proper postage affixed in an envelope addressed to "Commissioner for Patents, Alexandria, Virginia 22313-1450"

Feb. 15

 (Hai Jiang)